TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSIII)

2SK1382

Relay Drive, Motor Drive and DC-DC Converter Applications

• 4 V gate drive

• Low drain-source ON resistance : $RDS (ON) = 15 \text{ m}\Omega \text{ (typ.)}$ • High forward transfer admittance : $|Y_{fs}| = 47 \text{ S (typ.)}$

• Low leakage current $IDSS = 100 \mu A (max) (VDS = 100 V)$

• Enhancement-mode : $V_{th} = 0.8 \sim 2.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	100	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	100	V	
Gate-source voltage		V_{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	60	Α	
	Pulse (Note 1)	I _{DP}	240		
Drain power dissipation (Tc = 25°C)		P_{D}	200	W	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Thermal Characteristics

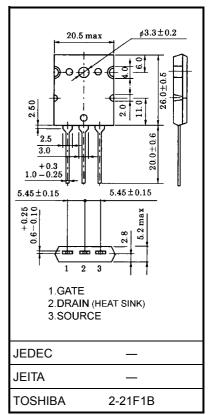
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.625	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	35.7	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

This transistor is an electrostatic sensitive device.

Please handle with caution.

Unit: mm



Weight: 9.75 g (typ.)

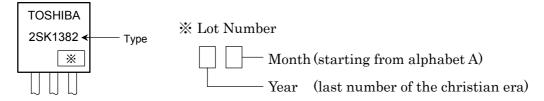
Electrical Characteristics (Ta = 25°C)

Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±20 V, V _{DS} = 0 V	_	_	±100	nA
Drain cut-off cur	rent	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	100	_	_	V
Gate threshold v	roltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Drain-source ON resistance		Б	V _{GS} = 4 V, I _D = 30 A	-	20	29	
		R _{DS} (ON)	V _{GS} = 10 V, I _D = 30 A	-	15	20	mΩ
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 30 A	30	47	_	S
Input capacitanc	е	C _{iss}			7000	_	pF
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		400	_	
Output capacitance		C _{oss}			2700	_	
Switching time	Rise time	t _r	V_{GS} V_{OV} V_{OUT} V_{OUT} V_{DD} V_{OUT} V_{DD} V_{DD} V_{DD}	_	16	_	- ns
	Turn-on time	t _{on}		_	55	_	
	Fall time	t _f		_	80	_	
	Turn-off time	t _{off}		_	280	_	
Total gate charg plus gate-drain)		Qg			176	_	_
Gate-source charge		Q _{gs}	$V_{DD} \approx 80 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		132	_	nC
Gate-drain ("miller") charge		Q _{gd}			44	_	

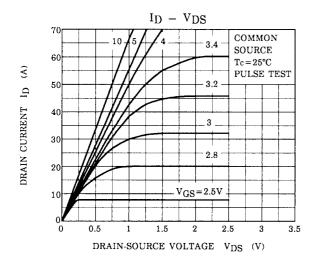
Source-Drain Ratings and Characteristics (Ta = 25°C)

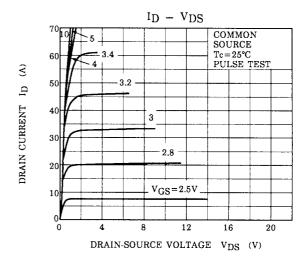
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	60	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	240	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 60 A, V _{GS} = 0 V	_	_	-1.6	V
Reverse recovery time	t _{rr}	I _{DR} = 60 A, V _{GS} = 0 V	_	300		ns
Reverse recovered charge	Q_{rr}	dl _{DR} / dt = 50 A / μs	_	0.75	1	μC

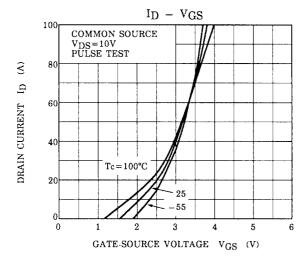
Marking

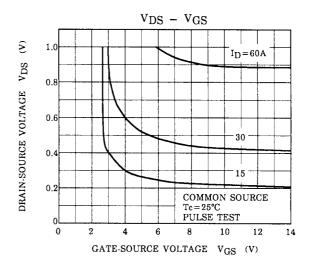


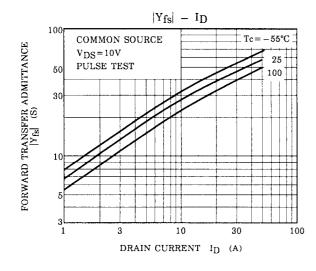
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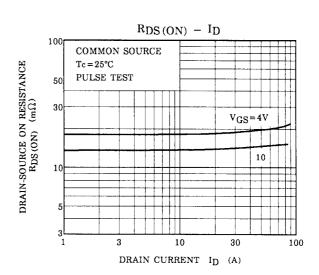


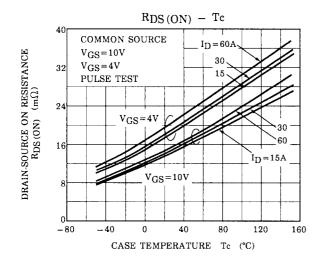


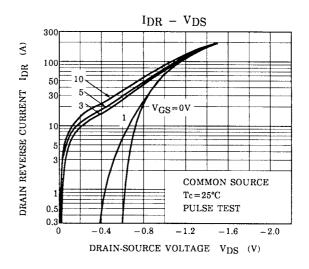


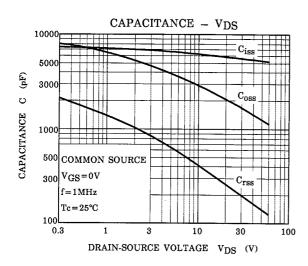


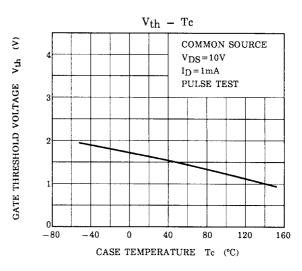


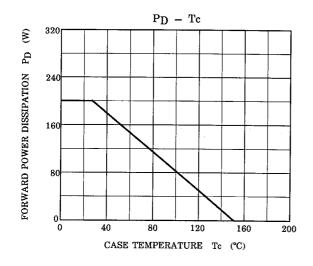


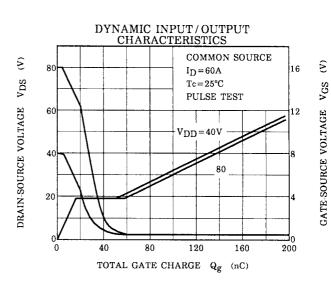




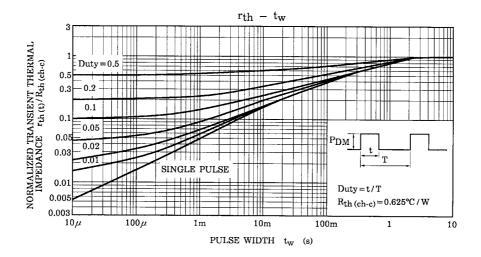


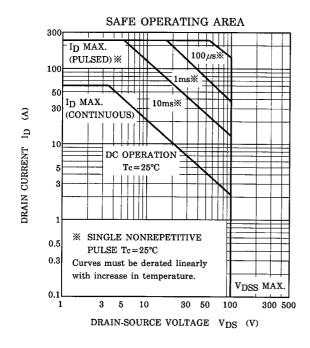






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